AMENDMENT

This listing of claims replaces all prior versions, and listings, of claims for this application.

 (Currently Amended) A process for obtaining a bulk gallium-containing nitridemonocrystal from supercritical ammonia-containing solution in the presence of a mineralizer, wherein nitride monocrystal, comprising:

contacting ammonia with a mineralizer comprising a Group I azide in a pressurized reaction vessel to form —using ammonia as solvent and Group I element azides and optionally Group II element azides as mineralizer, a supercritical ammonia-containing solution including comprising an ion of a Group I element; and optionally Group II element ions is first obtained to dissolve next

dissolving a gallium-containing feedstock at a dissolution temperature and/or-dissolution and pressure condition under which the gallium feedstock dissolves in the supercritical ammonia-containing solution; and then

crystallizing a gallium-containing nitride is erystallized from the supereritieal solution on the a surface of at least one a seed at [[the]] a crystallization temperature and/or crystallization and pressure condition.

wherein the crystallization temperature and/or crystallization and pressure is selected according to the condition is determined using a temperature coefficient of solubility and a pressure coefficient of solubility of the gallium-containing nitride to be crystallized.

2. (Currently Amended) A process for obtaining a bulk gallium-containing nitride monocrystal, comprising: from supercritical ammonia-containing solution in the presence of Group I and optionally Group II element-containing mineralizer, wherein when gallium-containing nitride has a negative temperature coefficient of solubility and a positive pressure coefficient of solubility in supercritical ammonia-containing solution, in the presence of Group I and optionally Group II element-containing mineralizer, in a pressurized reaction vessel—using Group I element azides and optionally Group II element azides as mineralizers—

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contacting ammonia with a mineralizer comprising a Group I azide in a pressurized reaction vessel at a condition under which a gallium-containing nitride has a negative temperature coefficient of solubility and a positive pressure coefficient of solubility, forming a supercritical ammonia-containing solution including comprising an ion of a Group I element; and optionally Group II element ions is first obtained to dissolve next

dissolving a gallium-containing feedstock at a dissolution temperature and/or dissolution and pressure; and then condition under which the gallium-containing feedstock dissolves in the supercritical ammonia-containing solution; gallium-containing nitride is erystallized from the supercritical solution on the surface of at least one seed by means of bringing the temperature to erystallization temperature and/or the pressure to crystallization pressure,

obtaining a super-saturation of the supercritical ammonia-containing solution at a crystallization temperature and pressure condition having a temperature higher than that of the dissolution temperature and pressure condition or a pressure lower than that of the dissolution temperature and pressure condition; and the crystallization temperature being higher than the dissolution temperature and/or the crystallization pressure being lower than the dissolution pressure at least at the crystallization zone of the pressurized reaction vessel, where the seed is placed—so that super-saturation of the supercritical solution with respect to the seed is achieved—and then

crystallizing a gallium-containing nitride on a surface of a seed by maintaining the supersaturation of the supercritical ammonia-containing solution is maintained at the level at which spontaneous crystallization of [[the]] nitride may be neglected, while crystallization of the galliumcontaining nitride is carried out on the seed is negligible.

(Currently Amended) Process according to claim 1, wherein [[the]] gaseous
nitrogen, produced during [[the]] decomposition of the azide, is at least partially evacuated from the
system before the re-crystallization crystallizing step is started.

- (Currently Amended) Process The process according to claim 1, wherein as-a the
 crystallized gallium-containing nitride—the nitride having has a general formula Al_xGa_{1-x}N, where
 0≤x<1 is crystallized.
- (Currently Amended) Process according to claim 1, wherein the azide moneralizers are mineralizer is selected from the group consisting of LiN₃, NaN₃, KN₃, CsN₃ and mixtures thereof.
- (Currently Amended) Process The process according to claim 5, wherein the mineralizer [[used]] contains at least one compound selected from the group consisting of LiN₃, NaN₃, KN₃ and CsN₃.
- (Currently Amended) Process The process according to the claim 6, wherein the mineralizer contains NaN₃ and KN₃ mixed in arbitrary molar ratio.
- (Currently Amended) <u>Process The process</u> according to the claim 6, wherein the mineralizer contains NaN₃ and LiN₃ mixed in arbitrary molar ratio.
- (Currently Amended) Process The process according to the claim 6, wherein the mineralizer contains KN₃ and LiN₃ mixed in arbitrary molar ratio.
- 10. (Currently Amended) Process The process according to the claim 6, wherein the mineralizer <u>further</u> contains [[also]] Group I <u>element-containing compound other than azide</u>, and optionally Group II element—containing-compound(s) other than azides.
- 11. (Currently Amended) Process The process according to claim 1, wherein the Group I element-azides are introduced into the system azide is added in a molar ratio of azides azide to ammonia ranging from 1:200 to 1:2.
- 12. (Currently Amended) Process The process according to claim 1, wherein [[a]] the seed erystal with at least comprises a crystalline layer of Group XIII element element-containing nitride; preferably gallium-containing nitride; having a dislocation density less than 10⁷ / cm² is-used.
- (Currently Amended) Process <u>The process</u> according to claim 1, wherein <u>the seed</u> comprises a structure having a number of surfaces spaced adequately far apart from each other,

arranged on a primary substrate and susceptible to [[the]] a lateral overgrowth of a crystalline mitrides is used as a seed nitride.

- 14. (Currently Amended) Process The process according to claim 1, wherein a monocrystalline nitride layer that is obtained having has the same or better quality as [[it]] the gallium-containing nitride monocrystal gets thicker.
- 15. (Currently Amended) Process The process according to claim 13, wherein the seed contains the primary substrate made of a crystalline nitride of Group XIII elements element.
- 16. (Currently Amended) Process The process according to claim 15, wherein the seed contains the primary substrate made of gallium nitride [[- GaN]].
- 17. (Currently Amended) Process The process according to claim 15, wherein the seed contains the primary substrate made of a crystalline material such as sapphire, spinel, ZnO, SiC or Si, and wherein the primary substrate made of [[the]] a material reacting with reactive to a supercritical ammonia-containing solution is covered with a protective layer, preferably made of a nitride containing Group XIII elements or metallic Ag, prior to formation of a monocrystalline nitride layer.
- (Currently Amended) Process The process according to claim 1, wherein the bulk nitride monocrystal obtained consists essentially of gallium nitride [[- GaN]].
- 19. (Currently Amended) Process The process according to claim 1, wherein the bulk nitride monocrystal obtained contains any of the following elements: Ni, Cr, Co, Ti, Fe, Al, Ag, Mo, W, Si and Mn.
- 20. (Currently Amended) Process The process according to claim 1, wherein some surfaces a surface of the seed are is covered with a mask layer prior to formation of a monocrystalline nitride layer.
 - 21-30. (Canceled)
- (Currently Amended) A method for epitaxy creating an epitaxial layer on a nitride monocrystal, comprising:

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obtaining a bulk nitride monocrystal by a process according to claim 1; and 21 as substrate for epitaxy and creating epitaxy

growing an epitaxial layer on the nitride monocrystal.

- 32. (Currently Amended) The method of claim 31, wherein the bulk nitride monocrystal has at least one epitaxial layer of the same or different Group XIII element element-containing nitride, deposited by a MOCVD, HVPE or MBE method as a template for opto-electronic devices.
- 33. (Original) The method of claim 32, wherein the epitaxial layer is doped with one or more dopants.
- 34. (Currently Amended) A bulk nitride monocrystal obtained by a process according to claim 1, having a reduced content of impurities in form of oxygen, as compared to a nitride monocrystal obtained from a supercritical solutions solution having a different qualitative composition than that used in claim 1.
 - 35. (Canceled)
- 36. (New) A process according to claim 1, wherein the mineralizer further comprises a Group II azide and the supercritical ammonia-containing solution further comprises an ion of a Group II element.
- 37. (New) A process according to claim 2, wherein the mineralizer further comprises a Group II azide and the supercritical ammonia-containing solution further comprises an ion of a Group II element.
- 38. (New) A process according to claim 10, wherein the mineralizer further comprises a Group II element-containing compound other than an azide.
- (New) A process according to claim 17, wherein the protective layer comprises a Group XIII element-containing nitride or a metallic Ag.